IEEE Computer Society

TTTC: Test Technology Technical Council

TTTC IN GENERAL

PURPOSE: The Test Technology Technical Council is a volunteer professional organization sponsored by the IEEE Computer Society. The goals of TTTC are to contribute to members' professional development and advancement and to help them solve engineering problems in electronic test, and help advance the state-of-the-art. In particular, TTTC aims at facilitating the knowledge flow in an integrated manner, to ensure overall quality in terms of technical excellence, fairness, openness, and equal opportunities.

MEMBERSHIP: Membership is open to all individuals interested in test engineering at a professional level.

DUES: There are NO dues for TTTC membership and no parent-organization membership requirements.

BENEFITS: The TTTC members benefit from personal association with other test professionals. They may have the opportunity to be involved on a wide range of committees. They receive appropriate and updated information and announcements. There are substantial reductions in fees for TTTC-sponsored meetings and tutorials for members of IEEE and/or IEEE Computer Society.

TTTC ACTIVITIES

TECHNICAL MEETINGS: To spread technical knowledge and advance the state-of-the-art, TTTC sponsors many well-known conferences and symposia and holds numerous regional and topical workshops worldwide.

STANDARDS: TTTC initiates, nurtures and encourages new test standards. TTTC-initiated Working Groups have produced numerous IEEE standards, including the 1149 series used throughout the industry.

TECHNICAL ACTIVITIES: TTTC sponsors a number of Technical Activity Committees (TACs) that address emerging test technology topics and guide a wide range of activities.

TUTORIALS and EDUCATION: TTTC sponsors a comprehensive Test Technology Educational Program (TTEP). This program provides opportunities for design and test professionals to update and expand their knowledge base in test technology, and to earn official accreditation from IEEE TTTC, upon the completion of four full day tutorials proposed by TTEP.

TTTC CONTACT

TTTC On-Line: The TTTC Web Site at http://tab.computer.org/tttc offers samples of the TTTC Newsletter, information about technical activities, conferences, workshops and standards, and links to the Web pages of a number of TTTC-sponsored technical meetings.

Becoming a MEMBER: Becoming a TTTC member is extremely simple. You may either contact by phone or e-mail the TTTC office, or fill out and submit a TTTC application form, or visit the membership section of the TTTC web site.

TTTC OFFICE: 1474 Freeman Drive, Amissville, VA 20106, USA
Phone: +1-540-937-8280  Fax: +1-540-937-7848  E-mail:tttc@computer.org
TTTC-Sponsored Technical Meetings in 2007
For the most current information, please visit the TTTC website (http://tab.computer.org/tttc)

2/27-3/2 Pacific Northwest Test Workshop (BAST), Bodega Bay, CA, USA  S. Ma; E. McCluskey
3/5-3/7 International Test Synthesis Workshop (ITSW), San Antonio, TX, USA  S. Patil
3/11-3/14 Latin American Test Workshop (LATW), Cuzco, Peru  C. Silva Cardenas; Y. Zorian
4/3-4/4 Workshop on Silicon Errors in Logic - System Effects (SELSE), Austin, TX, USA  W. Bartlett; P. Sandy
4/11-4/13 Design & Diagnosis of Electronic Circuits & Systems Workshop (DDECs), Krakow, Poland  E. Gramatovà
4/16-4/20 Design, Automation and Test in Europe (DATE), Nice, France  R. Lauwereins
5/6 Workshop on Test of Wireless Circuits and Systems (WTTW), Berkeley, CA, USA  R. Aitken; J.L. Carbonero
5/6-5/10 VLSI Test Symposium (VTS), Berkeley, CA, USA  P. Prinetto
5/9-5/10 Int’l Workshop on Open Source Test Technology Tools (IOST3), Berkeley, CA, USA  B. West
5/13-5/15 Austin Conference on Integrated Systems & Circuits (ACISC), Austin, TX  J. Abraham; M. McDermott
5/13-5/16 Workshop on Signal Propagation on Interconnects (SPI), Genova, Italy  F. Canavero; H. Grabiniski
5/16-5/18 North Atlantic Test Workshop (NATW), Boxborough, MA, USA  S. Ozev
5/20-5/24 European Test Symposium (ETS), Freiburg, Germany  B. Becker
5/23-5/24 International Silicon Debug and Diagnosis Workshop (SDD), Freiburg, Germany  R. Aitken
5/24-5/25 European Board Test Workshop (EBTW), Freiburg, Germany  J. Webster
5/31-6/1 Design & Test of Defect-Tolerant Nanoscale Architectures (NANOARCH), San Diego, USA  D. Hammerstrom; R. Karr
6/3-6/4 Int’l Conference on Microelectronics Systems Education (MSE), San Diego, CA, USA  M. Johnson
6/3-6/6 Semiconductor Wafer Test Workshop (SWTW), San Diego, CA, USA  J. Broz; W. Mann
6/18-6/20 International Mixed-Signals Test Workshop (IMSTW), Póvoa de Varzim, Portugal  J. Machado da Silva
6/18-6/20 GHz/Gbps Test Workshop (GTW), Póvoa de Varzim, Portugal  D. Keezer
7/9-7/11 International On-Line Testing Symposium (IOLTS), Crete, Greece  M. Nicolaidis; A. Paschalis
8/TBD International Workshop on Memory Technology, Design and Test (MTDT)  J. Chou
9/7-9/10 East-West Design and Test Symposium (EWDTS), Yerevan, Armenia  V. Hahanov; Y. Zorian
9/12-9/14 Board Test Workshop (BTW), Fort Collins, CO, USA  W. Eklow
9/26-9/28 Int’l Symposium on Defect & Fault Tolerance in VLSI Systems (DFTS), Rome, Italy  A. Salsano; N. Touba
10/9-10/11 Asian Test Symposium (ATS), Beijing, P.R. China  X. Li; K. Cheng
10/12-10/13 Workshop on RTL and High Level Testing (WRTLTL), Beijing, P.R. China  X. Li; P. Song
10/23-10/25 International Test Conference (ITC), Santa Clara, CA, USA  J. Sibert
10/25-10/26 Int’l Workshop on Design for Manufacturability & Yield (DIMY), Santa Clara, CA, USA  Y. Zorian
10/25-10/26 ATE: Vision 2020, Santa Clara, CA, USA  E. Volkerink
10/25-10/26 Int’l Workshop on Current & Defect Based Testing (DBT), Santa Clara, CA, USA  H. Manhaeve; M. Tahoori
10/10/TBD International Workshop on Microprocessor Test and Verification (MTV), Austin, TX, USA  M. Abadir
11/8 –11/9 Int’l High Level Design Validation and Test Workshop (HLDVT), Irvine, CA, USA  M. Hsiao
12/5-12/6 Int’l Workshop on Testing Embedded and Core-Based System-Chips (TECS), Online  Y. Zorian
12/16-12/18 International Design & Test Workshop (IDT), Cairo, Egypt  H. El Tahawy, Y. Zorian

TTTC Office
1474 Freeman Drive  Phone: +1-540-937-8280
Amissville, VA 20106  Fax: +1-540-937-7848
USA  E-mail: tttc@computer.org

http://tab.computer.org/tttc